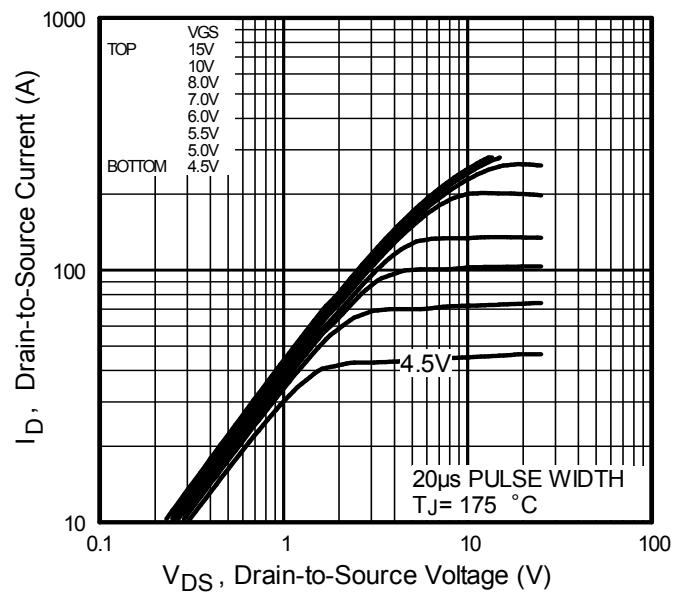
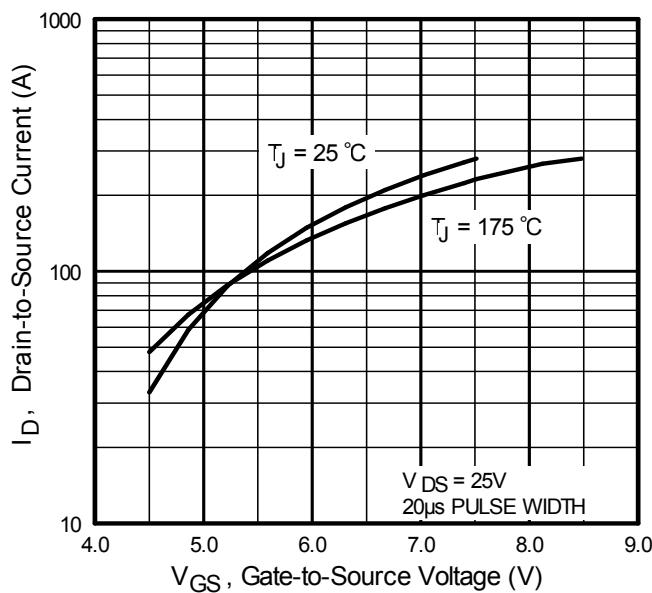
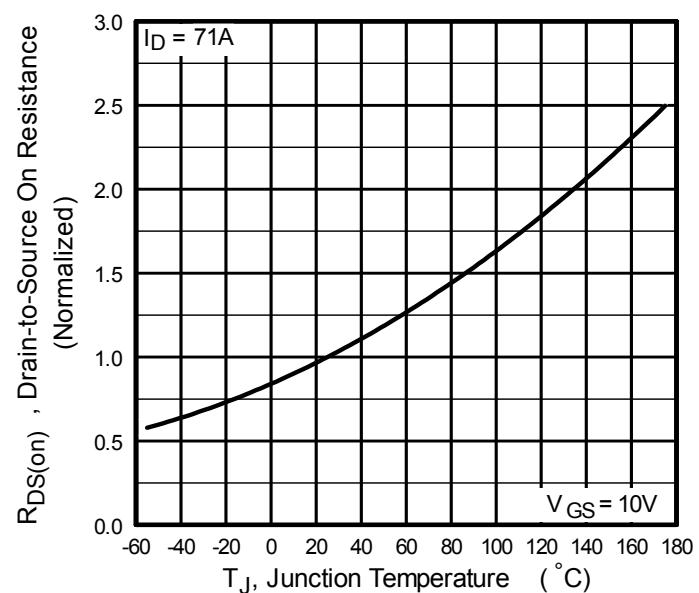
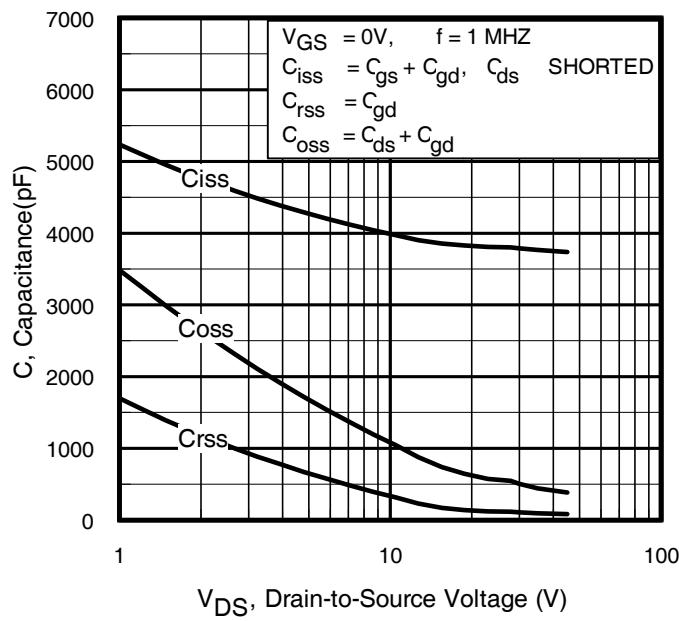
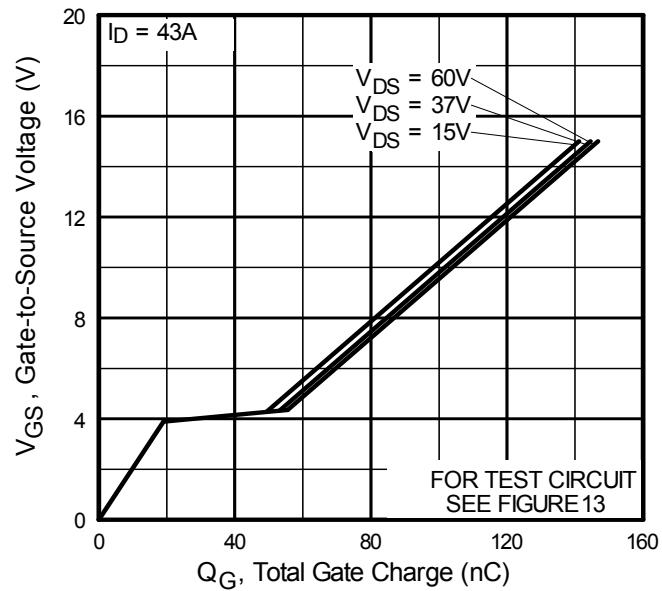
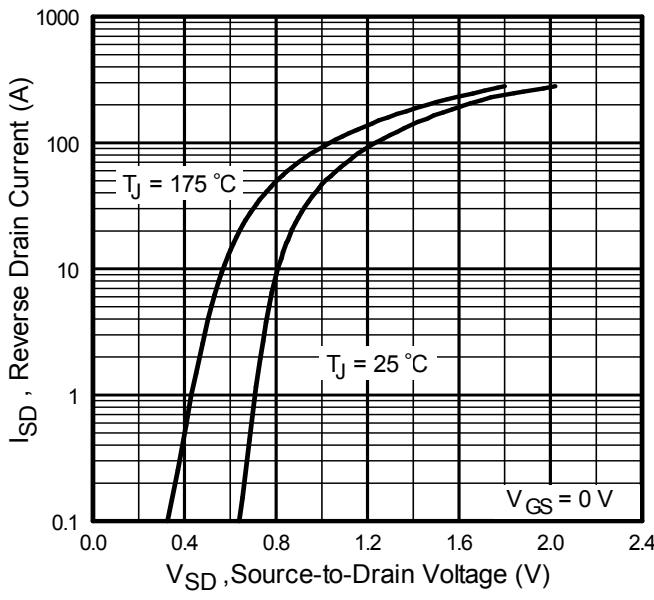
**Fig. 1** Typical Output Characteristics**Fig. 2** Typical Output Characteristics**Fig. 3** Typical Transfer Characteristics**Fig. 4** Normalized On-Resistance Vs. Temperature



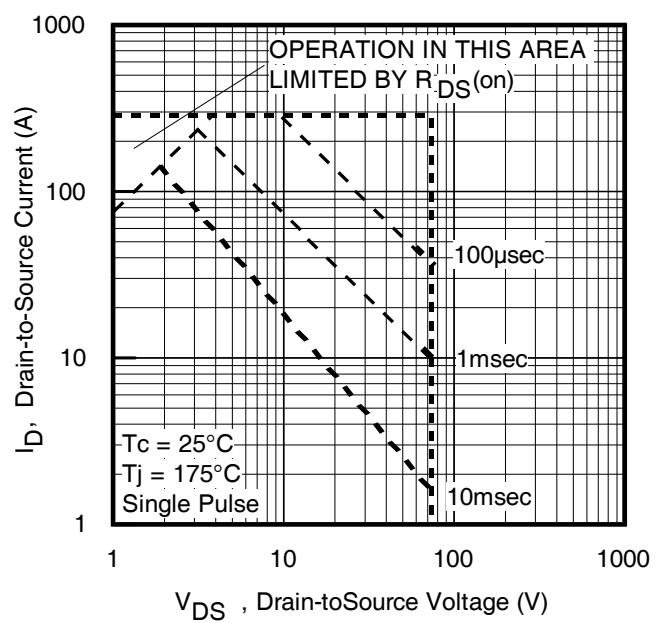
**Fig 5.** Typical Capacitance vs.  
Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge vs.  
Gate-to-Source Voltage



**Fig. 7** Typical Source-to-Drain Diode  
Forward Voltage



**Fig 8.** Maximum Safe Operating Area

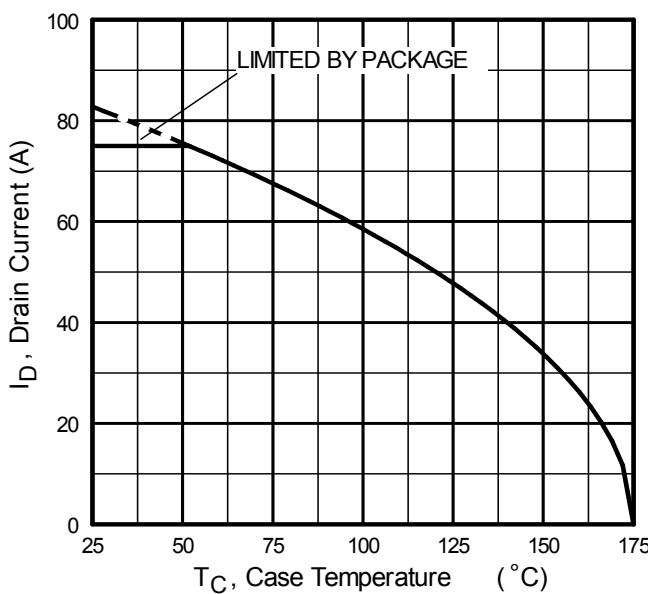


Fig 9. Maximum Drain Current vs. Case Temperature

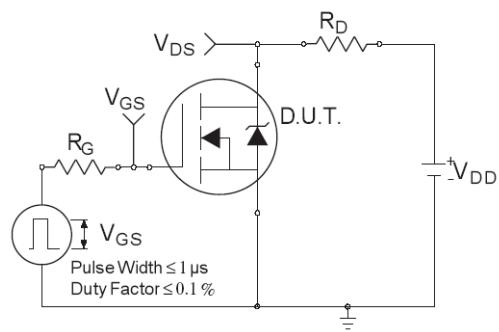


Fig 10a. Switching Time Test Circuit

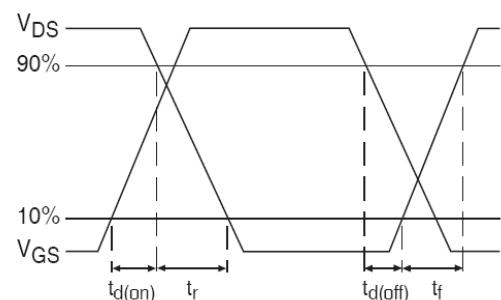


Fig 10b. Switching Time Waveforms

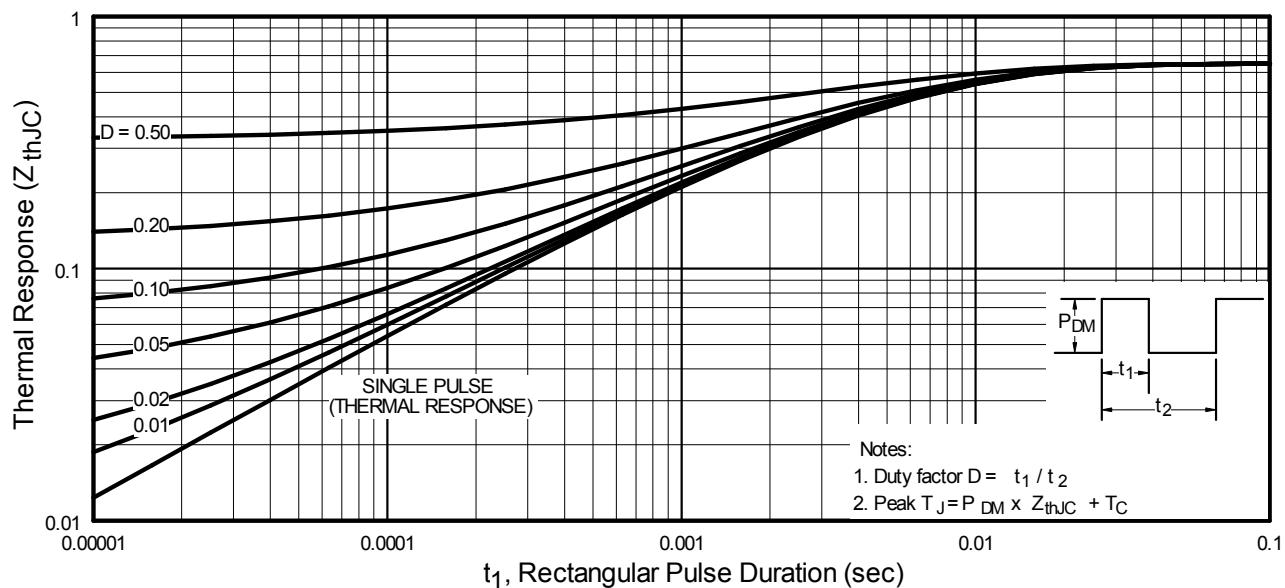
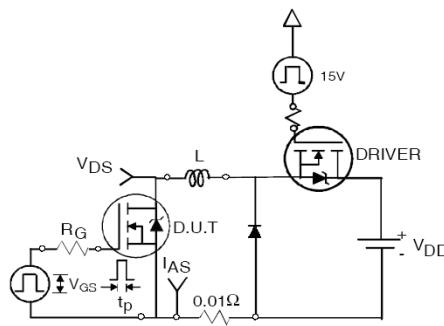
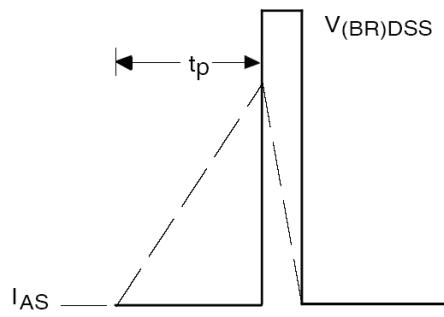


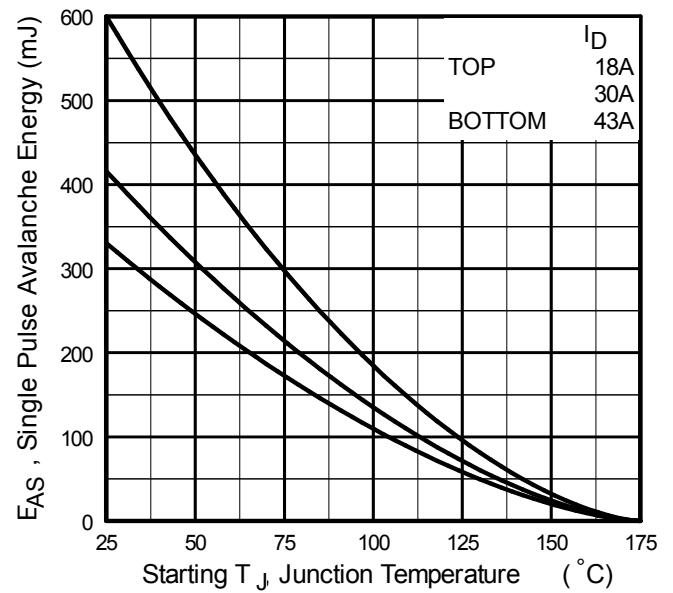
Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



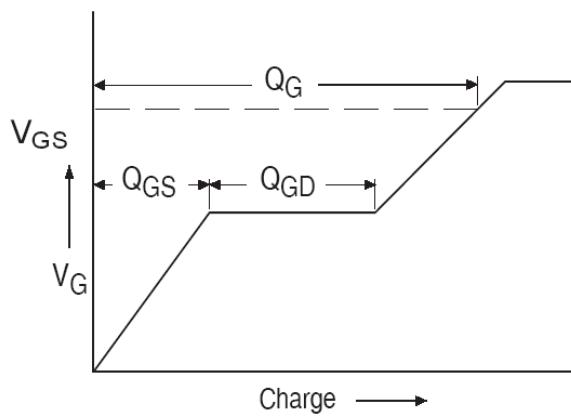
**Fig 12a.** Unclamped Inductive Test Circuit



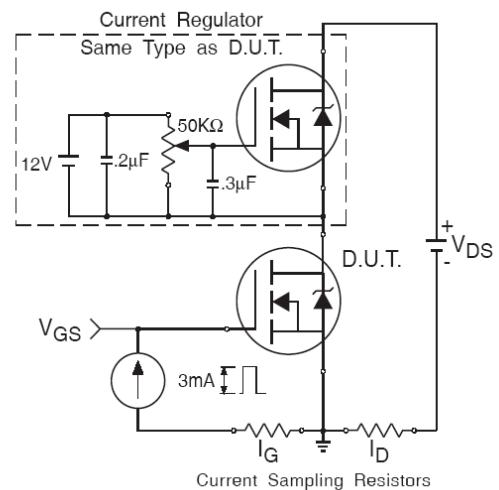
**Fig 12b.** Unclamped Inductive Waveforms



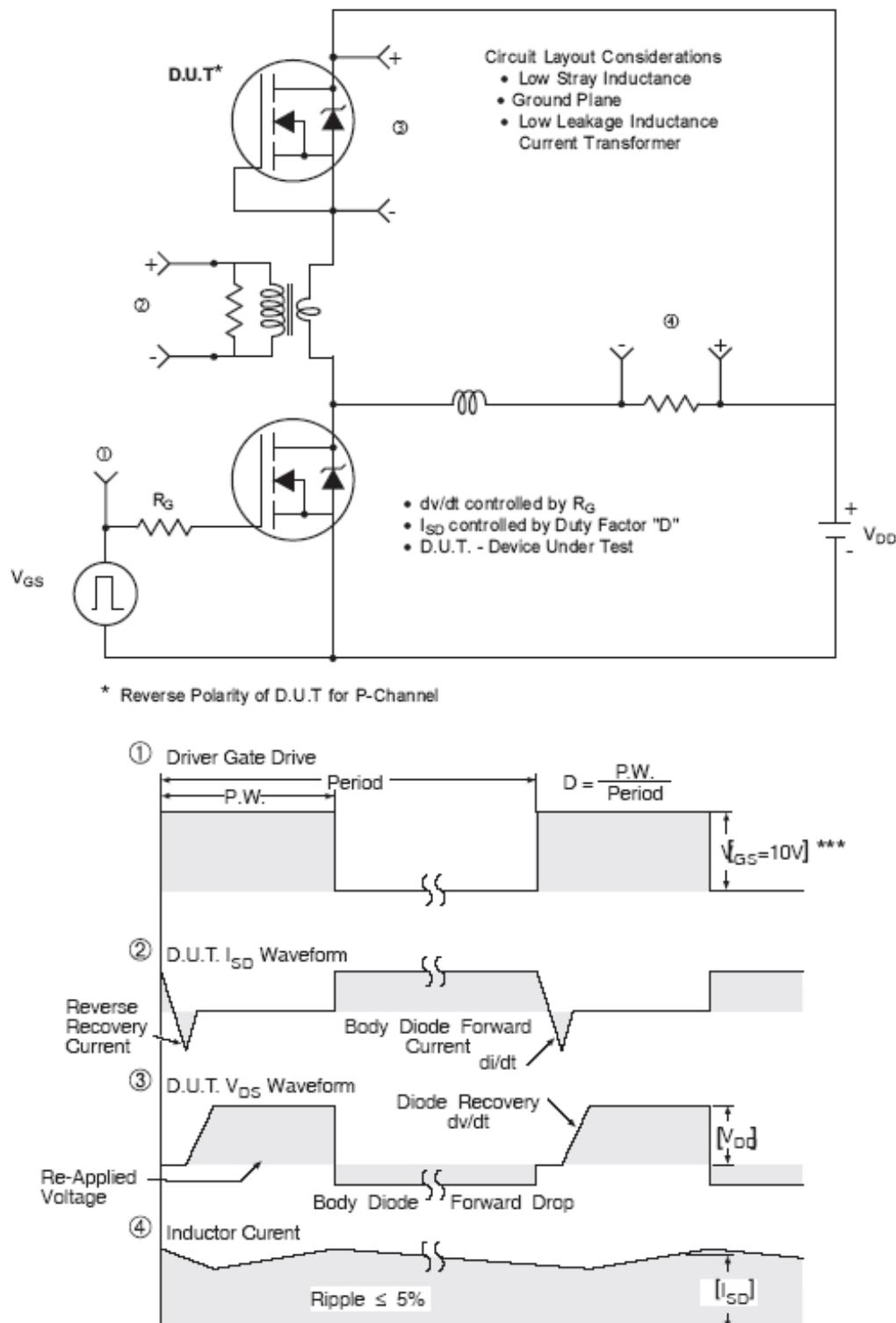
**Fig 12c.** Maximum Avalanche Energy vs. Drain Current



**Fig 13a.** Gate Charge Waveform



**Fig 13b.** Gate Charge Test Circuit



**Fig 14.** Peak Diode Recovery  $dv/dt$  Test Circuit for N-Channel HEXFET® Power MOSFETs



